TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

TC74HC00AP,TC74HC00AF,TC74HC00AFN

Quad 2-Input NAND Gate

The TC74HC00A is a high speed CMOS 2-INPUT NAND GATE fabricated with silicon gate C^2 MOS technology.

It achieves the high speed operation similar to equivalent LSTTL while maintaining the CMOS low power dissipation.

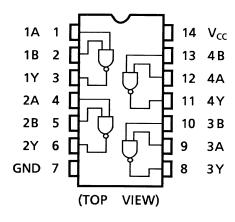
The internal circuit is composed of 3 stages including buffer output, which provide high noise immunity and stable output.

All inputs are equipped with protection circuits against static discharge or transient excess voltage.

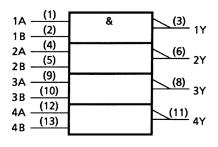
Features

- High speed: $t_{pd} = 6 \text{ ns (typ.)}$ at $V_{CC} = 5 \text{ V}$
- Low power dissipation: $I_{CC} = 1 \mu A \text{ (max)}$ at $T_a = 25 \text{°C}$
- High noise immunity: $V_{NIH} = V_{NIL} = 28\% V_{CC}$ (min)
- Output drive capability: 10 LSTTL loads
- Symmetrical output impedance: $|I_{OH}| = I_{OL} = 4 \text{ mA (min)}$
- Balanced propagation delays: $t_{pLH} \simeq t_{pHL}$
- Wide operating voltage range: V_{CC} (opr) = 2 to 6 V
- Pin and function compatible with 74LS00

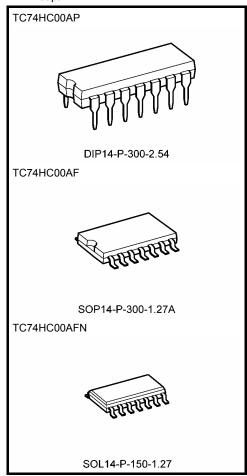
Pin Assignment



IEC Logic Symbol



Note: xxxFN (JEDEC SOP) is not available in Japan.



Weight

DIP14-P-300-2.54 : 0.96 g (typ.) SOP14-P-300-1.27A : 0.18 g (typ.) SOL14-P-150-1.27 : 0.12 g (typ.)

Truth Table

| Α | В | Υ |
|---|---|---|
| L | L | Н |
| L | Н | Н |
| Н | L | Н |
| Н | Н | L |

Absolute Maximum Ratings (Note 1)

| Characteristics | Symbol | Rating | Unit | |
|------------------------------------|------------------|-------------------------------|------|--|
| Supply voltage range | V_{CC} | –0.5 to 7 | V | |
| DC input voltage | V _{IN} | −0.5 to V _{CC} + 0.5 | V | |
| DC output voltage | V _{OUT} | −0.5 to V _{CC} + 0.5 | V | |
| Input diode current | I _{IK} | ±20 | mA | |
| Output diode current | lok | ±20 | mA | |
| DC output current | lout | ±25 | mA | |
| DC V _{CC} /ground current | Icc | ±50 | mA | |
| Power dissipation | PD | 500 (DIP) (Note 2)/180 (SOP) | mW | |
| Storage temperature | T _{stg} | -65 to 150 | °C | |

Note 1: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Note 2: 500 mW in the range of Ta = $-40 \text{ to } 65^{\circ}\text{C}$. From Ta = $65 \text{ to } 85^{\circ}\text{C}$ a derating factor of $-10 \text{ mW}/^{\circ}\text{C}$ shall be applied until 300 mW.

Operating Ranges (Note)

| Characteristics | Symbol | Rating | Unit |
|--------------------------|---------------------------------|-------------------------------------|------|
| Supply voltage | V _{CC} | 2 to 6 | V |
| Input voltage | V _{IN} | 0 to V _{CC} | V |
| Output voltage | V _{OUT} | 0 to V _{CC} | V |
| Operating temperature | T _{opr} | -40 to 85 | °C |
| | | 0 to 1000 (V _{CC} = 2.0 V) | |
| Input rise and fall time | t _r , t _f | 0 to 500 (V _{CC} = 4.5 V) | ns |
| | | 0 to 400 (V _{CC} = 6.0 V) | |

Note: The operating ranges must be maintained to ensure the normal operation of the device. Unused inputs must be tied to either VCC or GND.



Electrical Characteristics

DC Characteristics

| Characteristics | Symbol | Test Condition | | | Ta = 25°C | | Ta = -40 to 85°C | | Unit | |
|---------------------------|-----------------|---|----------------------------|-----|-----------|------|---------------------|------|------|----|
| | | | Vcc | | Min | Тур. | Max | Min | Max | |
| | | _ | | 2.0 | 1.50 | _ | _ | 1.50 | _ | |
| High-level input voltage | V _{IH} | | | 4.5 | 3.15 | _ | _ | 3.15 | _ | V |
| | | | | 6.0 | 4.20 | _ | _ | 4.20 | _ | |
| | | | | 2.0 | _ | _ | 0.50 | _ | 0.50 | |
| Low-level input voltage | V_{IL} | | _ | 4.5 | _ | _ | 1.35 | _ | 1.35 | V |
| l | | | | 6.0 | _ | _ | 1.80 | _ | 1.80 | |
| | | | | 2.0 | 1.9 | 2.0 | _ | 1.9 | _ | |
| | | | $I_{OH} = -20 \mu A$ | 4.5 | 4.4 | 4.5 | _ | 4.4 | _ | |
| High-level output voltage | V _{OH} | V _{IN} = V _{IH} or V _{IL} | | 6.0 | 5.9 | 6.0 | _ | 5.9 | _ | V |
| | | "" " | I _{OH} = -4 mA | 4.5 | 4.18 | 4.31 | _ | 4.13 | _ | |
| | | | $I_{OH} = -5.2 \text{ mA}$ | 6.0 | 5.68 | 5.80 | _ | 5.63 | _ | |
| | | V _{IN} = V _{IH} or V _{IL} | | 2.0 | _ | 0.0 | 0.1 | _ | 0.1 | |
| | | | $I_{OL} = 20 \mu A$ | 4.5 | _ | 0.0 | 0.1 | _ | 0.1 | |
| Low-level output voltage | V _{OL} | | | 6.0 | _ | 0.0 | 0.1 | _ | 0.1 | V |
| Tonago | | | I _{OL} = 4 mA | 4.5 | _ | 0.17 | 0.26 | _ | 0.33 | |
| | | | I _{OL} = 5.2 mA | 6.0 | _ | 0.18 | 0.26 | _ | 0.33 | |
| Input leakage current | I _{IN} | V _{IN} = V _{CC} or GND | | 6.0 | _ | _ | ±0.1 | _ | ±1.0 | μА |
| Quiescent supply current | Icc | V _{IN} = V _{CC} or GND | | 6.0 | _ | _ | 1.0 | _ | 10.0 | μА |

AC Characteristics ($C_L = 15 \text{ pF}$, $V_{CC} = 5 \text{ V}$, $Ta = 25^{\circ}\text{C}$, input: $t_r = t_f = 6 \text{ ns}$)

| Characteristics | Symbol | Test Condition | Min | Тур. | Max | Unit |
|------------------------|------------------|----------------|-----|------|-----|------|
| Output transition time | t _{TLH} | _ | _ | 4 | 8 | ns |
| | t _{THL} | | | | | |
| Propagation delay time | t _{pLH} | _ | | 6 | 12 | ns |
| | t _{pHL} | _ | | | '- | 113 |

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AC Characteristics ($C_L = 50 \text{ pF}$, input: $t_r = t_f = 6 \text{ ns}$)

| Characteristics Syr | Symbol | Test Condition | | Ta = 25°C | | | Ta = -40 to 85°C | | Unit |
|-------------------------------|------------------------|----------------|---------------------|-----------|------|-----|---------------------|-----|------|
| | • | | V _{CC} (V) | Min | Тур. | Max | Min | Max | |
| | | 2.0 | _ | 25 | 75 | _ | 95 | | |
| Output transition time | | _ | 4.5 | _ | 7 | 15 | _ | 19 | ns |
| t _{THL} | ЧHL | | 6.0 | _ | 6 | 13 | _ | 16 | |
| Propagation delay time tpHL | 4 | | 2.0 | _ | 27 | 75 | _ | 95 | |
| | - | _ | 4.5 | _ | 9 | 15 | _ | 19 | ns |
| | lрНL | | 6.0 | _ | 8 | 13 | _ | 16 | |
| Input capacitance | C _{IN} | _ | | _ | 5 | 10 | | 10 | pF |
| Power dissipation capacitance | C _{PD} (Note) | _ | | _ | 20 | _ | _ | _ | pF |

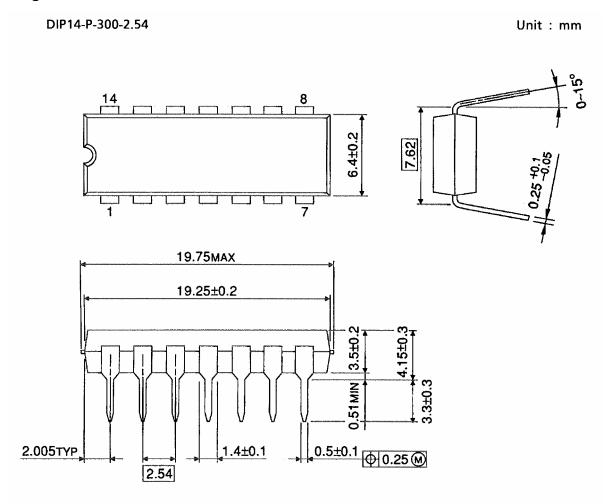
Note: C_{PD} is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

Average operating current can be obtained by the equation:

$$I_{CC}$$
 (opr) = $C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}/4$ (per gate)



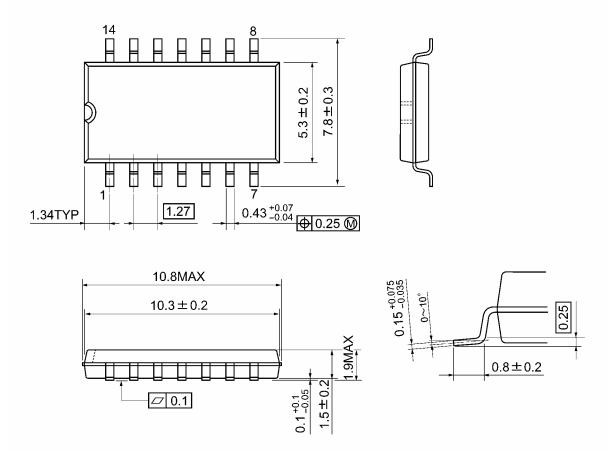
Package Dimensions



Weight: 0.96 g (typ.)

Package Dimensions

SOP14-P-300-1.27A Unit: mm

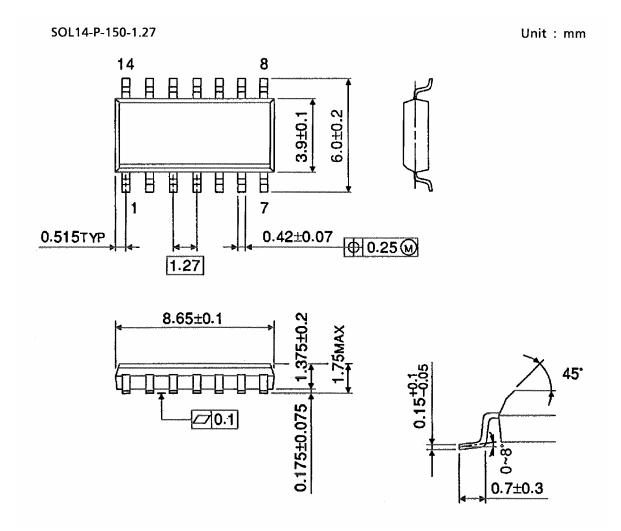


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Weight: 0.18 g (typ.)



Package Dimensions (Note)



Note: This package is not available in Japan.

Weight: 0.12 g (typ.)

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20070701-EN GENERAL

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